

COURSE SYLLABUS

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| University | Alexandru Ioan Cuza University of Iași | Course title | |
| Faculty | Physics | Experimental Methods in Physics of Materials | |
| Department | Physics | | |
| Domain | Physics | Course category (FC/SC/CC¹): FC | Term (1-4): 3 |
| Level | Postgraduate (MA) | Course type (Co/EI/F²): Co | |

I. Course structure

| Number of hours/week | | | | Credits | Total class hours/semester | Total hours of individual activity | Examination type (C/Ex/CE ³) | Teaching language |
|----------------------|---------|----------|---------|----------|----------------------------|------------------------------------|--|-------------------|
| Course | Seminar | Lab. | Project | 6 | 56 | 124 | Ex | English |
| 2 | | 2 | | | | | | |

II. Instructors

| | Academic degree ⁴ | Scientific degree | Name and surname | Faculty position (tenure/associate - organization) |
|------------|------------------------------|-------------------|---------------------|--|
| Course | Assoc. Prof. | PhD | Baban Cristian-Ioan | tenure |
| Seminar | Assoc. Prof. | PhD | Baban Cristian-Ioan | tenure |
| Laboratory | | | | |

III. Prerequisites

Solid state physics, Quantum mechanics, Physics of atoms and molecules

IV. Course objectives

The student will obtain good understanding of materials characterization by introducing the basic principles and performing experiences of a large range of techniques used to characterize different types of materials. After completion of the course, the student shall: have the ability to recommend appropriate methods for particular problems; be able to apply the knowledge obtained to elaborate a work plan in solving a particular problem; be able to explain the data obtained and the phenomena exhibited in the materials analysis

V. Course content

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|-------------------|---|
| Course | X-ray diffraction technique. Neutron diffraction Fundamentals of electron microscopy (SEM, TEM, Electron diffraction, STEM). Electron Probe Micro Analysis (EPMA) (EDS, WDS) Electron Energy-Loss Spectroscopy (EELS) Scanning tunneling microscopy and atomic force microscopy. Electron emission spectroscopies (XPS, AES, UPS). X-Ray Fluorescence (XRF) Ion scattering techniques and mass spectroscopy Vibrational spectroscopy (IR, Raman) Resonance techniques (NMR, ESR) Thermal analysis (DSC and DTA). Low temperature techniques. |
| Seminar | |
| Laboratory | 1. Qualitative and quantitative analysis of XRD patterns |

¹ FC – fundamental course, SC – specialty course, CC – complementary course

² Co – compulsory, EI – elective, F – facultative

³ C – colloquium, Ex – exam, CE – colloquium AND exam

⁴ Professor / Associate professor / Lecturer / Assistant professor / Teaching assistant

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| | <ol style="list-style-type: none"> 2. Interpretation of XPS spectra 3. Electrical conduction at low temperatures 4. Differential thermal analysis 5. Presentation on site of experimental equipments for materials characterization (SEM, XRD, XPS, XRF, AFM, IR, Raman) 6. Individual work for project elaboration and presentation |
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VI. Minimal required references

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| <ol style="list-style-type: none"> 1. V. Pop, I. Chicinaş, N. Jumate, Fizica Materialelor: Metode experimentale, Presa Universitară Clujeană, 2001 2. P.E.J. Flewitt, R.K. Wild, Physical Methods for Materials Characterisation, Institute of Physics, Bristol and Philadelphia, 1994. 3. R.C. Brundle et al., Encyclopedia of materials characterization :surfaces, interfaces, thin films London: Butterworth-Heinemann, 1992 |
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VII. Didactic methods

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| <p>lecture, explanation, conversation, debate, examples multimedia presentation experiment</p> |
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VIII. Assessment

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| Pre-conditions | Students should attend at least 50 % of course hours and 100 % laboratory work | |
| Exam dates | 1st Assessment | Individual project |
| | 2nd Assessment | Written examination |

| | Assessment means and methods | Percentage of the final grade |
|-----------------|---|--------------------------------------|
| Exam/Colloquium | written | 50 % |
| Seminar | | |
| Laboratory | free presentation of a specific project | 50 % |